Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/509,393	STUDER, CHRISTOPH
Examiner	Art Unit

Jinhee J. Lee

2831

SEARCHED					
Class	Subclass	Date	Examiner		
174	113R	7/23/2005	LEE		
	110R		1/		
0	115	1	V		
174	as above	1/6/2006	LEE		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
174	as above	7/23/2005	LEE	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Text Search Attached	7/23/2005	LEE	
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